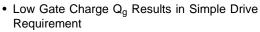


N-Channel 650 V (D-S)MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	650				
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	5			
Q _g (Max.) (nC)	11				
Q _{gs} (nC)	2.3				
Q _{gd} (nC)	5.2				
Configuration	Single				

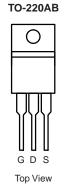
FEATURES

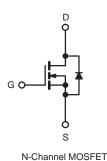




• Improved Gate, Avalanche and Dynamic dV/dt Ruggedness

- Fully Characterized Capacitance and Avalanche Voltage
- and Current
- Compliant to RoHS directive 2002/95/EC





PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	650		
Gate-Source Voltage			V_{GS}	± 30	V	
Continuous Drain Currente	V _{GS} at 10 V	T _C = 25 °C	I _D	2.0	А	
Continuous Drain Current	VGS at 10 V	T _C = 100 °C		1.28		
Pulsed Drain Current ^a			I _{DM}	8		
Linear Derating Factor				0.48	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	165	mJ	
Repetitive Avalanche Current ^a			I _{AR}	2	Α	
Repetitive Avalanche Energy ^a	E _{AR}	6	mJ			
Maximum Power Dissipation T _C = 25 °C			P_D	45	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.8	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature) ^d	for	10 s		300	7	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T_J = 25 °C, L = 24 mH, R_G = 25 Ω , I_{AS} = 3.2 A (see fig. 12).
- c. $I_{SD} \le 3.2$ A, $dI/dt \le 90$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.
- e. Drain current limited by maximum junction temperature.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	65	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	2.1	C/VV		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V_{DS}	V _{GS} :	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	Reference to 25 °C, I _D = 1 mA ^d		670	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	$V_{DS} = V_{GS}, I_D = 250 \mu A$		-	4.0	V
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 30 V		-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		V _{DS} = 650 V, V _{GS} = 0 V V _{DS} = 520 V, V _{GS} = 0 V, T _J = 125 °C		-	25 250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 1 A b	-	4.0	-	Ω
Forward Transconductance	9 _{fs}	V _{DS}	= 50 V, I _D = 1 A	3.9	-	-	S
Dynamic		1					1
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,		417	-	
Output Capacitance	C _{oss}		$V_{DS} = 25 \text{ V},$	-	45	-	1
Reverse Transfer Capacitance	C _{rss}	f = 1	f = 1.0 MHz, see fig. 5		5	-	_
Output Capacitance	C _{oss}		V _{DS} = 1.0 V, f = 1.0 MHz	-	912	-	pF
		$V_{GS} = 0 V$	V _{DS} = 520 V, f = 1.0 MHz	-	26		
Effective Output Capacitance	C _{oss} eff.		V _{DS} = 0 V to 520 V ^c	-	42	-	
Total Gate Charge	Q_g		I _D = 1.2 A, V _{DS} = 400 V	ı	-	11	nC
Gate-Source Charge	Q_gs	V _{GS} = 10 V		ı	-	2.3	
Gate-Drain Charge	Q_{gd}		see fig. 6 and 13 ^b		-	5.2]
Turn-On Delay Time	t _{d(on)}				14	-	<u> </u>
Rise Time	t _r		= 325 V, I _D = 1.2A	-	20	-	1
Turn-Off Delay Time	t _{d(off)}	$R_{G} =$	$R_G = 9.1 \Omega$, $R_D = 62 \Omega$, see fig. 10^b		34	-	- ns -
Fall Time	t _f				18	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	showing the	/ :/		-	2	A
Pulsed Diode Forward Current ^a	I _{SM}	p - n junction diode		i	-	8	
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 3.2 A, V _{GS} = 0 V ^b		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	- T _J = 25 °C, I _F = 3.2 A, dI/dt = 100 A/μs ^b		-	180	230	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	2.1	3.2	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)					L _D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 µs; duty cycle \leq 2 %.
- c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .
- d. t = 60 s, f = 60 Hz.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

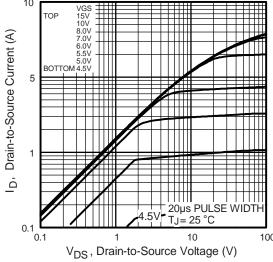


Fig. 1 - Typical Output Characteristics

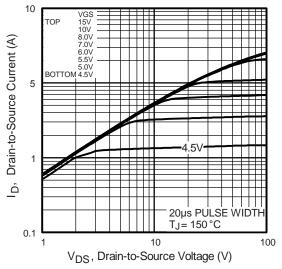


Fig. 2 - Typical Output Characteristics

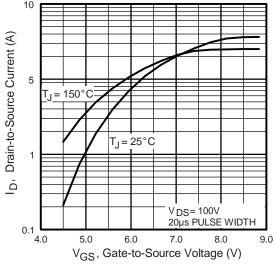


Fig. 3 - Typical Transfer Characteristics

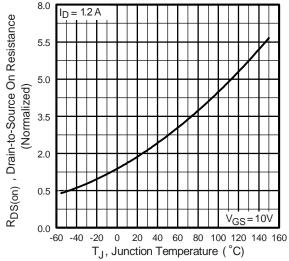


Fig. 4 - Normalized On-Resistance vs. Temperature



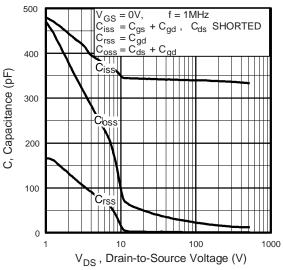


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

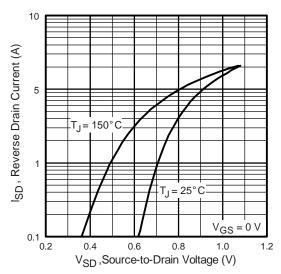


Fig. 7 - Typical Source-Drain Diode Forward Voltage

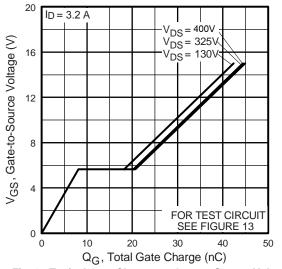


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

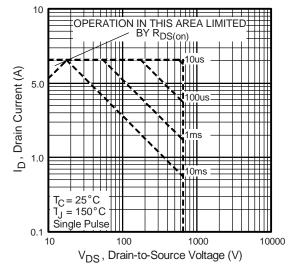


Fig. 8 - Maximum Safe Operating Area



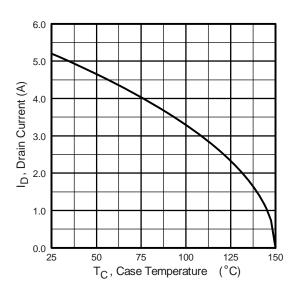


Fig. 9 - Maximum Drain Current vs. Case Temperature

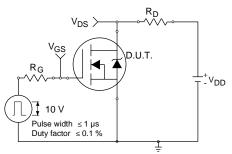


Fig. 10a - Switching Time Test Circuit

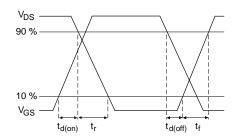


Fig. 10b - Switching Time Waveforms

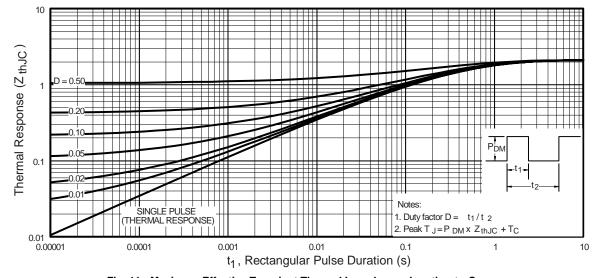


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

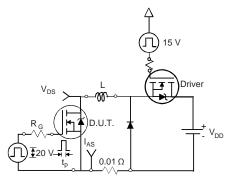


Fig. 12a - Unclamped Inductive Test Circuit

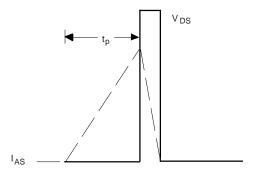


Fig. 12b - Unclamped Inductive Waveforms



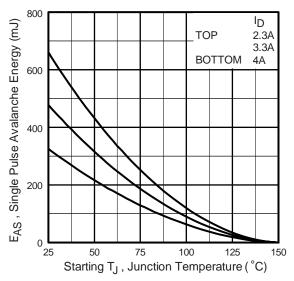


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

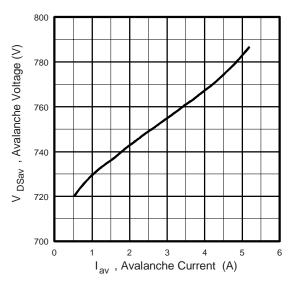


Fig. 12d - Typical Drain-to Source Voltage vs. Avalanche Current

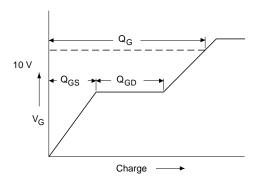


Fig. 13a - Basic Gate Charge Waveform

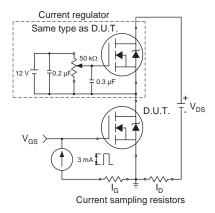
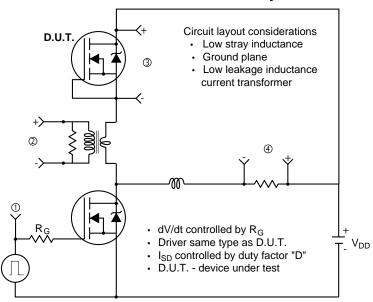
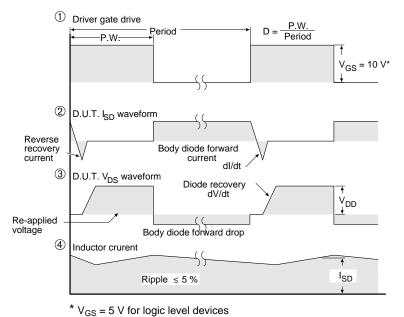


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



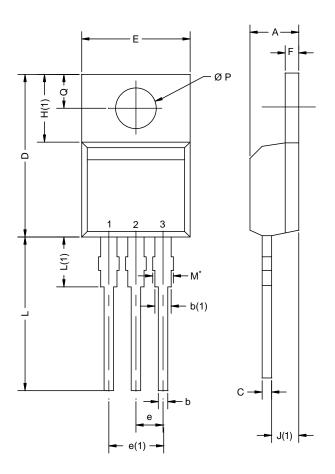


G

Fig. 14 - For N-Channel



TO-220AB



	MILLIM	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
E	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

Notes

 $^{^{\}star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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